Classical-to-stochastic Coulom b blockade cross-over in alum inum arsenide wires

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We report low temperature di erential conductance measurements in alum inum arsenide cleavededge overgrown quantum wires in the pinch-oregine. At zero source-drain bias we observe C oulom b blockade conductance resonances that become vanishingly small as the temperature is low ered below 250 m K. We show that this behavior can be interpreted as a classical-to-stochastic C oulom b blockade cross-over in a series of asym metric quantum dots, and ore a quantitative analysis of the temperature-dependence of the resonances lineshape. The conductance behavior at large sourcedrain bias is suggestive of the charge density wave conduction expected for a chain of quantum dots.

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Since the observation of C oulom b blockade (C B) in disordered m icron-long G aA s w ires [1], electrons in G aA s have been the preferred system of CB study due to their sm allm ass and long m ean-free-path, allow ing the necessary control of quantum con nem ent length scales below the mean free path to design shorter, single-resonance system s. However the original literature [1] also includes intriguing results in heavier-electron m ass disordered Si w ires which have proven harder to interpret, presum ably because they contain a multiplicity of resonances. Like the GaAsCB, the Sisystem shows a suppressed conductance for a range of gate voltage (V_{GD} , drain D grounded) and source-drain voltage (V_{SD}) which periodically closes at a resonance forming a diam ond-shaped conductance suppression in V_{SD} vs. V_{GD}. However unlike G aAs, the resonance peaks in Siwires are very small, and at nite V_{SD} bias outside of the diam ond region exhibit a com paratively large single peak followed by a continuous tail at larger V_{SD} . Theories have been proposed to explain this behavior [2, 3], but a quantitative con mation which extracts the model parameters from the data has been lacking. More recently, experiments on split-gate constrictions in the quantum Hall (QH) regime have shown

nite bias conductance traces strikingly sim ilar to that of the disordered Si w ire literature [4]. This behavior is linked to forward and reverse m oving Q H edge m odes coupled via an interaction region arti cially induced by the constriction. A lithough the one-dimensional (1D) system is comprised of G aAs electrons, the soft con ning potential of the split-gate region is expected to slow the m ode velocity, e ectively increasing the transport m ass in this system.

In this Letter, we present a disordered heavy-m ass A As wire system in the C oulom b blockade regime. Sim – ilar features to the above system s are observed and studied in detail. We propose that this behavior is universal to heavy-m ass disordered 1D systems at pincho, and we illustrate how quantitative inform ation about the relevant capacitances in the problem can be determined.

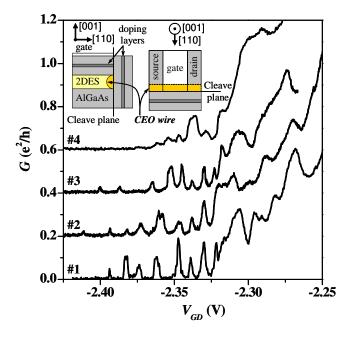


FIG.1: (Color) Conductance G vs. gate bias $V_{G\,D}$ for several $V_{G\,D}$ sweeps in the positive-voltage direction at a base electron temperature T = 100 m K. Beyond the fourth sweep it becomes increasingly di cult to resolve resonances. Each trace is o set by 0.2e^2 =h for clarity. Inset: schem atic of the sample.

We nd that the transport theories proposed by Ruzin, et al. [2] and Bakhvalov, et al. [3] for a series of weakly coupled dots are able to explain the CB resonances and the CB conductance outside the diam ond, respectively. A sw ith standard CB, the shape of the diam ond allow sus to deduce the capacitance of the principle dot in the wire, but we then proceed, according to Ref. [2], to t the tem – perature dependence of the resonance to a classical-tostochastic CB crossoverwhich allow sus to determ ine the capacitance of the second limiting dot. Large bias conductances outside the C oulom b diam ond are then show n to be consistent with a charge density ow ing through a chain of dots described in Ref. $[\beta]$ pinned at low energies by the CB gap.

The quantum wire samples are fabricated from a 150A-wide, modulation-doped A lAs 2D electron system (2DES) sandwiched between two AIG aAs spacers and grown on a (001) GaAs substrate (see inset to Fig. 1). The substrate is cleaved in-situ at the perpendicular (110) plane and overgrown with another modulationdoped barrier [5]. Electrons in the two degenerate Xvalleys accumulate along the cleaved edge of the 2DES and form the doubly valley-degenerate 1D system. A 1 m-wide m etalgate on the substrate depletes the 2DES underneath and varies the wire density in the segment located below it. The 2DES regions on each side of the gate serve as ohm ic contacts, and conductance m easurements are performed in a 2-point con guration using V_{ac} ' 10 V < k_B T and standard lock-in techniques. The e ective mass in the direction of the wire is $m = 0.33 m_0$ in units of the free-electron m ass, which is a factor of 5 larger than in CEO GaAswires [6], leading to a stronger role for interactions at the sam e density. Samples are cooled down in a dilution refrigerator with an electron base temperature T = 100 mK. The substrate and the cleaved-edge are illum inated at 10K with two infrared light-em itting diodes.

Figure 1 depicts combs of conductance resonances at $T\,=\,100\,m\,K$ as the gate bias $V_{G\,D}\,$ is scanned past the pinch-o threshold. The rst $V_{\!\!G\,D}\,$ sweep after illum ination and at base $T\,$ yields quasi-periodic resonances. Upon sweeping $V_{G\,D}\,$ repeatedly in the same direction some resonances appear to be quite robust while others shift. By the fourth gate sweep m ost resonances have vanished and those remaining are lum ped close to threshold.

W e interpret this behavior as C oulom b blockade (CB) in a disorder potential in analogy with its original discovery in disordered Si wires [L]. As the wire is depleted, the disorder potential isolates OD islands of electrons throughout the wire, whose capacitance de ness a charging energy which periodically blocks single electron transport. P resum ably, cycling V_{GD} a ects the distribution of ionized dopants underneath the gate [7], inducing variations in the potential background seen by the wire at each cycle. How ever by narrowing the gate bias window it is possible to preserve one resonance upon multiple V_{GD} cycles and perform a system atic study of it, as we now demonstrate.

W e study two resonances A and B in detail. Each is observed in a separate cooldown, and is well isolated and located at a similar $V_{G\,D}$ away from threshold. Fig. 2a illustrates the in uence of T on resonance A, and Fig.2b sum marizes the T-dependence of the peak conductance $G_{m\,ax}$ and of the resonance area A for A and B. Two distinct tem perature regimes are apparent in Fig.2b: $G_{m\,ax}$ is weakly T-dependent above 250m K, then sharply falls o at lower T. A (T) is linear for T > 250m K but drops

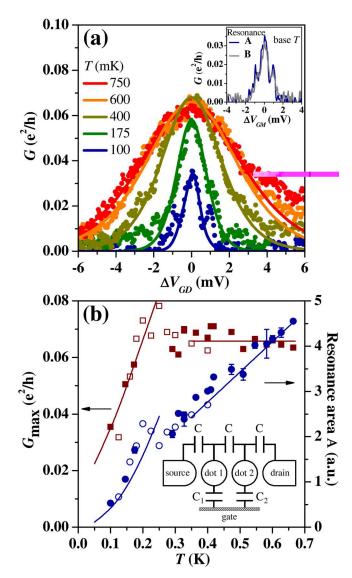


FIG.2: (Color) (a) Evolution of a resonance A with tem perature T.Curve ts of the model of R ef. [2] for two asymmetric dots in series are shown assuming capacitances described in the text. Resonances A and B are shown in the inset to share a similar triple-peak structure at base T. (b) Conductance peak $G_{m ax}$ (red) and resonance area A (blue) as a function of T.Filled (hollow) symbols correspond to resonance A (B). A is twice the integrated area of the left half of the resonance; error bars quantify the left-right asymmetry at higher tem peratures, and correspond to jA full area j=2. Lines are t to the model of R ef. [2].

rapidly for T < 250 mK. At base T both resonances resolve into a striking triple-peak (inset to Fig.2a).

The T-dependence of the resonance lineshape in Fig.2a suggests that transport within our wire is limited by two asymmetric quantum dots. This regime has been addressed theoretically by Ruzin, et al. [2] for the case of two quantum dots in series, wherein tunneling is incoherent and density is tuned by a common gate (see inset to Fig. 2b). Following the notation of Ref. [2], individual

dots 1 and 2 are characterized by their capacitances to the gate C_1 and C_2 . The inter-dot capacitance as well as the capacitance between each dot and either source or drain is assumed to be equal to C. The total capacitance of dot i is $C_i^{tot} = C_i + 2C$. Transport through the double dot structure occurs only when both dots have an available energy level within $k_B T$ of the Fermi energy. In the case of strongly asym metric dots, e.g. C_1^{tot} C_2^{tot} , the large di erence in the level spacings $e^2 = C_1^{\text{tot}}$ $e^2 = C_2^{tot}$ makes this condition increasingly di cult to meet at low T, leading to stochastic CB and vanishing resonances. On the other hand, for $k_B T > e^2 = C_2^{tot}$, the model in Ref. [2] explains that the level spacing in dot 2 is not relevant and transport is dom inated by the charging of the single dot 1. Indeed, looking at Fig. 2b, G_{max} (T) and A (T) above 250 mK resemble the behavior of a single dot resonance in the classical CB regime [8].

We therefore posit $e^2 = C_2^{\text{tot}} = k_B$ $250 \,\mathrm{m\,K} = 21 \,\mathrm{eV}$ $(C_2^{tot} = 7:6 \text{ fr})$ as the cross-over energy scale below which the double dot structure becom es relevant [2]. Given that the periodicity of CB oscillations is determ ined by the sm allest gate-dot capacitance C₁ C_2 , we use the energy conversion $@E_F = @V_{GD} = 40 \text{ m eV} = V \text{ m easured}$ from the thermal linewidth [8], along with the typical resonance spacing V_{GD} ' 10 mV [14], to obtain $e^2 = C_1^{\text{tot}}$ / 400 eV ($C_1^{\text{tot}} = 0.4 \text{ fF}$). The resonant conductance through the double dot can now be calculated following the model in Ref. [2] and using the estimated $C_1^{tot} = C_2^{tot}$ ratio. The lineshape evolution is captured by the simple analytical solution obtained in the limit of small interdot capacitance C. The complete set of calculated resonance lineshapes are plotted in Fig. 2a, with the solid lines in Fig. 2b representing the calculated peak conductances and areas.

The gate-dot capacitance of the current-limiting dot is $C_1 = e V_{GD}$ ' 0:016 fF [15]. C_1 is small compared to C_1^{tot} so that the nite coupling capacity C is expected to play a role. Indeed, after Refs. [2, 9], a nite C does not change the overall T-dependence of G_{max} and A but could explain the emergence of ner features at low temperature, such as the multiple peaks shown in the inset to Fig.2a.

Having demonstrated evidence of a classical-tostochastic CB crossover in A As wires, we now focus on the source-drain bias dependence and analyze the nonlinear conduction through the wire. The color plot in Fig. 3a reports the di erential conductance dI=dV_{SD} as a function of V_{GD} and V_{SD} at T = 100 m K. D ata are collected by sweeping V_{SD} and stepping V_{GD}. All features evolve sm oothly, without any signi cant trapped charge events. CB diam onds de ned as regions of vanishing conductance are highlighted with dashed lines. N ote that the vanishingly sm all resonances at V_{SD} = 0 are not visible on this color scale. N ear threshold, CB diam onds highlighted in white are visible. A dditional diam onds with a steeper dV_{GD} =dV_{SD} slope are observed at m ore nega-

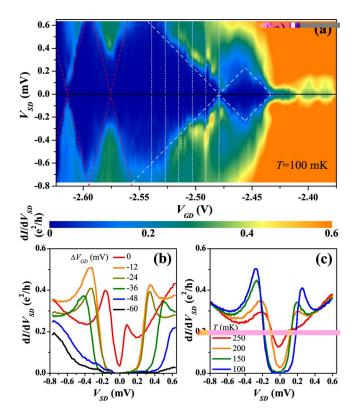


FIG.3: (Color) (a) Di erential conductance $dI=dV_{S\,D}$ as a function of source-drain dc bias $V_{S\,D}$ and gate bias $V_{G\,D}$ at T = 100 mK. D iam onds are highlighted. (b) Subset showing traces at xed $V_{G\,D}$ indicated by the vertical dashed lines in (a). The conductance at $V_{G\,D}$ = 0 and $V_{S\,D}$ = 0 corresponds to the maximum of a resonance peak. (c) Temperature dependence of $dI=dV_{S\,D}$ at xed $V_{G\,D}$ 50 mV from pinch-o , taken from a di erent dataset.

tive V_{GD} values (red dashed lines). Fig. 3b shows several dI=dV_{SD} vs. V_{SD} traces at xed $V_{\!GD}$ as indicated by the vertical dashed lines in Fig. 3a: a gap structure centered at $V_{SD} = 0$ develops beyond pinch-o as T is low ered (Fig. 3c). Sim ilar non-linear features are observed for three separate cooldowns of the same sam ple (data not shown). Note how the condition of maximum resonant conduction at the center of the CB diam ond $V_{GD} = 0$ in Fig. 3b corresponds to a strong m in im um in dI=dV vs. V_{SD} similar to the observations in Ref. [1]. The dot size for the cooldown of Fig. 3 can be estimated, as before, from V_{GD} ' 38mV, yielding L ' 30 nm. Comparing with the estimate for L obtained from Fig. 1 indicates that the dot size uctuates with cooldown. In addition, an analysis of the red and white diam ond slopes shows that the lim iting dot becom esm ore and m ore isolated as the electron density decreases.

The gap structure in the di erential conductance $dI=dV_{SD}$ (V_{SD}) reported in Fig. 3 displays peculiar features. Outside of the CB gap the conductance of Fig. 3b shows a single peak followed by a monotonically increasing conductance. This has to be contrasted with stan-

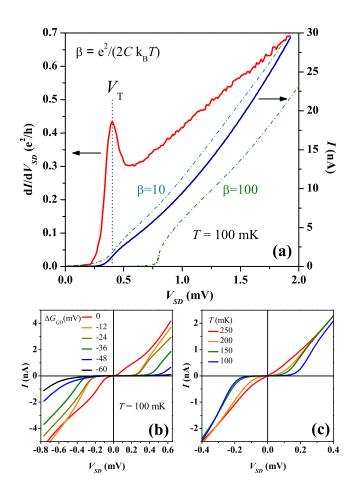


FIG. 4: (Color) (a) Typical $dI=dV_{\text{SD}}$ (V_{SD}) and integrated current I (V_{SD}). is ratio of the charging energy over the therm alenergy. (b) Integrated I (V_{SD}) from traces of Fig.3b. (c) Temperature dependence of I (V_{SD}) after integration of $dI=dV_{\text{SD}}$ in Fig.3c.

dard CB behaviorwhich would show a series of peaks outside the gap region. This rst peak also shows the tem – perature broadening expected for CB features (Fig. 3c), but the wings at higher voltage show no obvious T – dependence.

This conductance threshold outside of the CB gap is rem iniscent of what one would expect for a de-pinned charge density wave, as rst proposed in such systems in Ref. [1]. This e ect is more easily recognized if the $dI=dV_{SD}$ data are integrated to give I V_{SD} . Fig. 4a shows an example of a $dI=dV_{SD}$ curve integrated to reveal a step-like current on set in $I = V_{SD}$ outside of the CB region. The full dataset of Figs. 3b and 3c are integrated for comparison in Figs. 4b and 4c. W e can now identify the peak in dI=dV_{SD} in Fig. 4a as a threshold voltage V_T at which point the current is at the center of its step-like rise, and the charge ow becomes depinned. Ref. [3] provides a quantitative description of how a chain of coupled dots in series can support current ow in the form of charge solitons, so for com parison we plot the two

theoretical curves available from Ref. [3] in Fig. 4a along with the experimental data. These curves represent the cases $= e^2 = (2C k_B T) = 10$ and 100, appropriate to the estimated capacitance C = 0.2 fF that yields ' 45 at $T = 100 \text{ m K} \cdot \text{Ref.}$ [3] also predicts that the conductance threshold V_T (V_{GD}) resembles C oulom b diamonds that do not close, as observed here in experiment. We propose

that ow of charge density through the chain of quantum dots is pinned by the CB gap of the dot with the smallest capacitance, and outside of this gap the charge ow s through the dot chain as a soliton waves as predicted for such system s.

We note that di erent T-dependent resonance areas were recently measured in another 1D experiment by Auslaender, et al. [13], and were interpreted as evidence for Luttinger liquid physics. Yet the fact that the dotchain m odel successfully explains our measurements suggests that our disordered quantum wire is in a qualitatively di erent conductance regime.

In sum m ary, we have provided evidence that disordered A IA s C EO wires break up into a series of weaklycoupled quantum dots at low electron density. The tem perature dependence of resonances is interpreted as a classical-to-stochastic C oulom b blockade cross-over dom inated by two asym m etric dots. D i erential conductance m easurem ents indicate a threshold for conductance outside the C oulom b diam ond which can be explained with the soliton m odel of conductance in a chain of coupled quantum dots. The analysis provided here should prove useful for identifying transport m echanism s in sim ilar large-m ass, one-dim ensional disordered system s.

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- [14] This value was measured as the distance between resonance A and its immediate neighbor. This also agrees with data in Fig. 1.
- [15] The dot length L can be extracted [12] by tting C_1 to an electrostatic m odel of a cylinder-shaped dot C_1 ' 2 ln(2d=R) L, where is the absolute dielectric constant of A IG aA s, d = 380 nm is the gate-dot distance and R = 7:5 nm is the dot radius, yielding L ' 100 nm.